

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10526520	SCHULIST ET AL.
	Examiner	Art Unit
	Nguyen, Hai V	2618

SEARCHED

Class	Subclass	Date	Examiner
370	335	12/22/2007	HN

SEARCH NOTES

Search Notes	Date	Examiner
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	12/21/2007; 01/03/2008	HN

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner